

Appl. No. 09/871,596  
Amtd. Dated February 20, 2004  
Reply to Office Action of October 20, 2003

Attorney Docket No. 81754.0061  
Customer No.: 26021

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1. (Currently Amended) A method for testing a physical layer device including a link layer interface, a physical layer logic circuit to be connected to said link layer interface, and a plurality of ports to be connected to said physical layer logic circuit are provided beforehand in said physical layer device;

*in testing, said test link layer circuit is connected to said physical layer logic circuit through said link layer interface, and said test physical layer logic circuit is connected to a first port that is one of said plurality of ports, and said first port is connected to a second port that is one of said plurality of ports through an external bus, and the second port is connected to said physical layer logic circuit through said plurality of ports; and*

*said link layer interface, said physical layer logic circuit, and said plurality of ports are tested.*

2. (Currently Amended): A physical layer device with test circuits, said physical layer device including a link layer interface, a physical layer logic circuit to be connected to said link layer interface, and a plurality of ports to be connected to said physical layer logic circuit, said physical layer device characterized by compromising;

*a test link layer circuit for establishing, in testing, a connection with said link layer interface, a connection with said physical layer logic circuit through said*

Appl. No. 09/871,596  
Amdt. Dated February 20, 2004  
Reply to Office Action of October 20, 2003

Attorney Docket No. 81754.0061  
Customer No.: 26021

link layer interface and communicating predetermined data with said physical layer logic circuit; and

a test physical layer logic circuit for establishing, in testing, a connection with said plurality of ports, wherein a first port that is one of said plurality of ports, is connected to a second port that is one of said plurality of ports through an external bus, where the first and second ports are connected to a connection with said physical layer logic circuit through said plurality of ports and communicating predetermined data with said physical layer logic circuit.

3. (Original) A physical layer device with test circuits according to claim 2, characterized in that:

    said link layer interface includes a switch for selectively establishing a connection with an external link layer device or said test link layer circuit; and

    a predetermined port from among said plurality of ports includes a switch for selectively establishing a connection with said physical layer logic circuit or said test physical layer logic circuit.

4-13. (Canceled)